signetics

64-BIT BIPOLAR SCRATCH PAD MEMORY (16x4 RAM) 82S25

FEBRUARY 1975

DIGITAL 8000 SERIES TTL/MEMORY

DESCRIPTION

The 82S25 is a 64-bit, Schottky clamped TTL, Read-Write Random Access Memory ideal for use in scratch pad and high-speed buffer memory applications.

The 82S25 is a fully decoded memory array organized as 16 words of 4 bits each, with separate input and output lines. It features PNP inputs, one chip enable line, and open collector outputs for ease of memory expansion.

The outputs of the 82S25 assume a logic "1" state during write. This allows both memory inputs and outputs to share a common bus for minimizing interconnections, and more effective utilization of common I/O circuitry.

The 82S25 is available in the commercial and military temperature ranges. For the commercial temperature range (0°C to +75°C) specify N82S25, B or F. For the military temperature range (−55°C to +125°C) specify S82S25, F only.

FEATURES

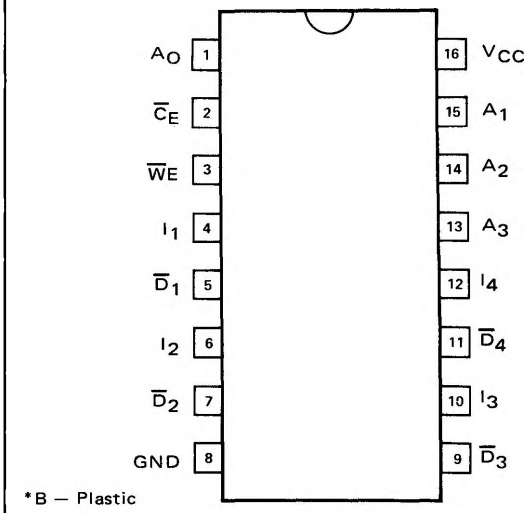
- ORGANIZATION – 16 X 4
- ADDRESS ACCESS TIME:
  S82S25 – 60ns, MAXIMUM
  N82S25 – 50ns, MAXIMUM
- WRITE CYCLE TIME:
  S82S25 – 50ns, MAXIMUM
  N82S25 – 35ns, MAXIMUM
- POWER DISSIPATION – 6.25mW/BIT, TYPICAL
- INPUT LOADING:
  S82S25 – (−150μA) MAXIMUM
  N82S25 – (−100μA) MAXIMUM
- OUTPUT BLANKING DURING WRITE
- ON-CHIP ADDRESS DECODING
- OPEN COLLECTOR OUTPUTS
- 16 PIN CERAMIC DIP

APPLICATIONS

SCRATCH PAD MEMORY
BUFFER MEMORY
PUSH DOWN STACKS
CONTROL STORE

PIN CONFIGURATION

B, F PACKAGE*



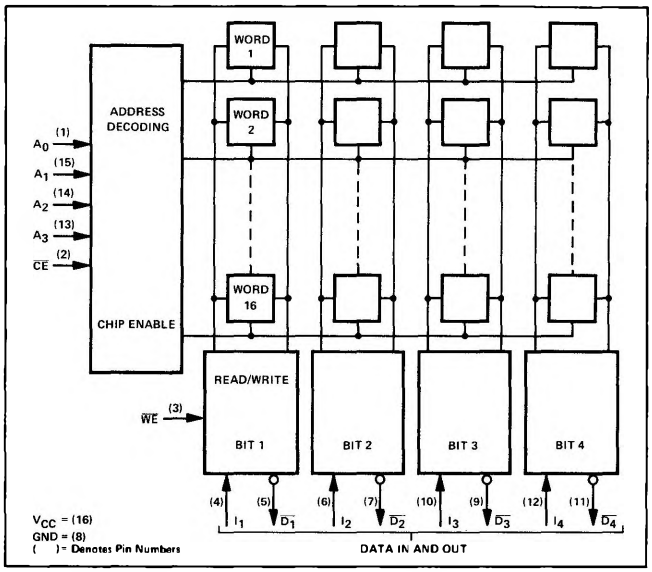
*B — Plastic
F — Cerdip

TRUTH TABLE

MODE	$\overline{CE}$	$\overline{WE}$	In	$\overline{Dn}$
Read	0	1	X	Complement of data stored
Write "0"	0	0	0	1
Write "1"	0	0	1	1
Disabled	1	X	X	1

X = Don't care.

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER[1]		RATING	UNIT
V_{CC}	Power Supply Voltage	+7	Vdc
V_{in}	Input Voltage	+5.5	Vdc
V_{OH}	High Level Output Voltage	+5.5	Vdc
T_A	Operating Temperature Range		
	(N82S25)	0° to +75°	°C
	(S82S25)	−55° to +125°	°C
T_{stg}	Storage Temperature Range	−65° to +150°	°C

ELECTRICAL CHARACTERISTICS

S82S25 $-55°C \leqslant T_A \leqslant +125°C$, $4.5V \leqslant V_{CC} \leqslant 5.5V$
N82S25 $0°C \leqslant T_A \leqslant +75°C$, $4.75V \leqslant V_{CC} \leqslant 5.25V$

PARAMETER		TEST CONDITIONS	S82S25[1,2,3]			N82S25[1,2,3]			UNIT
			MIN	TYP[8]	MAX	MIN	TYP[8]	MAX	
I_{IL}	"0" Input Current	V_{IN} = 0.45V		−10	−150		−10	−100	μA
I_{IH}	"1" Input Current	V_{IN} = 5.5V			25			10	μA
V_{IL}	"0" Level Input Voltage	V_{CC} = MIN			.80			.85	V
V_{IH}	"1" Level Input Voltage	V_{CC} = MAX	2.0			2.0			V
V_{IC}	Input Clamp Voltage	I_{IN} = −12mA, V_{CC} = MIN (Note 6)		−1.0	−1.5		−1.0	−1.5	V
V_{OL}	"0" Output Voltage	I_{OUT} = 16mA, V_{CC} = MIN (Notes 4, 5)		0.35	0.5		0.35	0.45	V
C_{IN}	Input Capacitance	V_{IH} = 2.0V, V_{CC} = 5.0V		5			5		pF
C_{OUT}	Output Capacitance	V_{OUT} = 2.0V, V_{CC} = 5.0V, $\overline{CE}$ = "1"		8			8		pF
I_{CC}	Power Supply Current	(Note 5)		80	120		80	105	mA
I_{OLK}	Output Leakage Current	$\overline{CE}$ = "1", V_{OUT} = 5.5V, V_{CC} = MIN		<1	100		<1.0	100	μA

NOTES:
1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. Positive current is defined as into the terminal referenced.
3. Positive logic definition: "1" = HIGH ≈ +5.0V; "0" = LOW ≈ GRD.
4. Output sink current is supplied through a resistor to V_{CC}.
5. All sense outputs in "0" state.
6. Test each input one at a time.
7. To guarantee a WRITE into the slowest bit.
8. Typical values are at V_{CC} = +5.0V and T_A = +25°C.

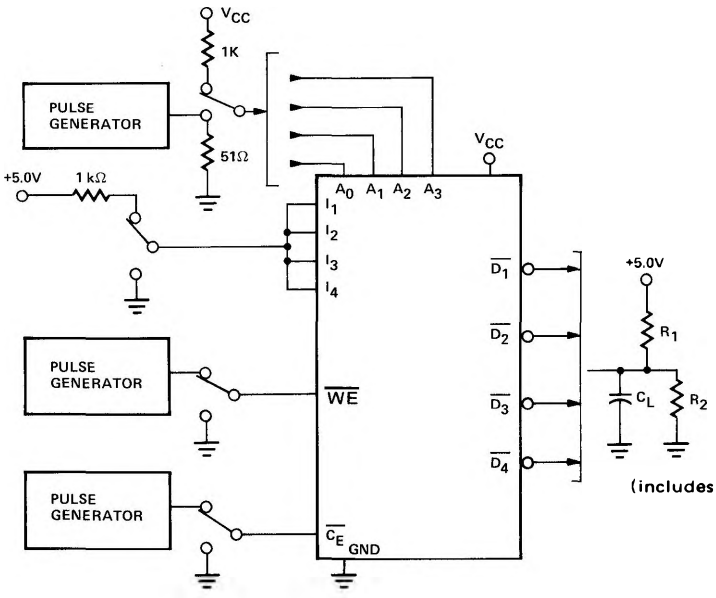
SWITCHING CHARACTERISTICS

S82S25 $-55°C \leq T_A \leq +125°C$, $4.5V \leq V_{CC} \leq 5.5V$
N82S25 $0°C \leq T_A \leq +75°C$, $4.75V \leq V_{CC} \leq 5.25V$

PARAMETER		TEST CONDITIONS	S82S25			N82S25			UNIT
			MIN	TYP[8]	MAX	MIN	TYP[8]	MAX	
Propagation Delays									
T_{AA}	Address Access Time			35	60		35	50	ns
T_{CE}	Chip Enable Access Time			20	35		20	35	ns
T_{CD}	Chip Enable Output Disable Time			20	35		20	35	ns
T_{WD}	Write Enable to Output Disable Time			20	30		20	25	ns
T_{WR}	Write Recovery Time			35	60		35	50	ns
Write Set-up Times		$R_1 = 270\Omega$ $R_2 = 600\Omega$							
T_{WSA}	Address to Write Enable	$C_L = 30pF$	10	−8		0	−8		ns
T_{WSD}	Data In to Write Enable		25	5		20	5		ns
T_{WSC}	$\overline{CE}$ to Write Enable		0	−5		0	−5		ns
Write Hold Times									
T_{WHA}	Address to Write Enable		10	0		5	0		ns
T_{WHD}	Data In to Write Enable		10	−3		5	−3		ns
T_{WHC}	$\overline{CE}$ to Write Enable		5	0		5	0		ns
T_{WP}	Write Enable Pulse Width (Note 7)		30	18		30	18		ns

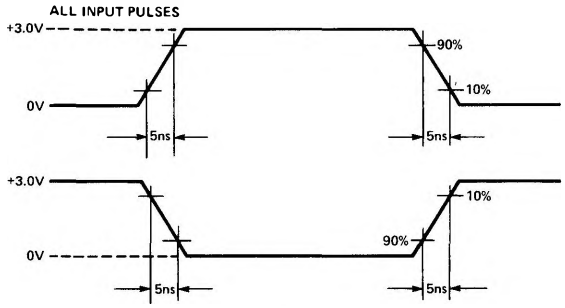
AC TEST LOAD AND WAVEFORMS

LOADING CONDITION



(includes jig and scope capacitance)

INPUT PULSES

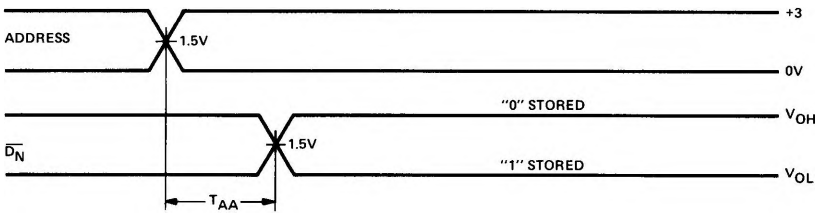


MEASUREMENTS: ALL CIRCUIT DELAYS ARE MEASURED AT THE +1.5V LEVEL OF INPUTS AND OUTPUT.

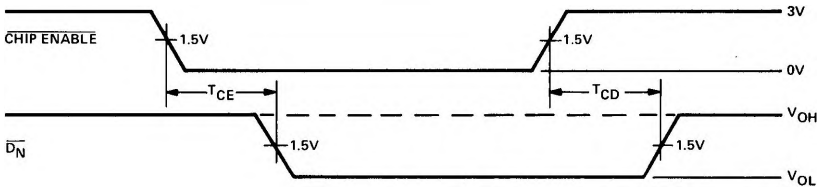
SWITCHING PARAMETERS MEASUREMENT INFORMATION

READ CYCLE

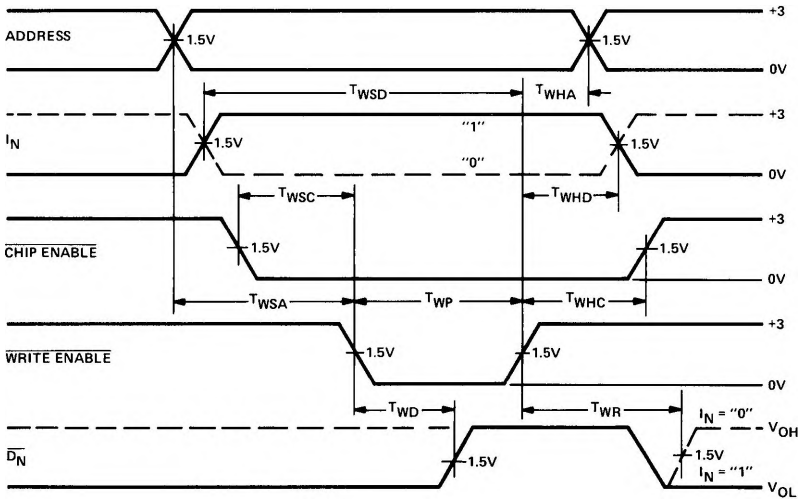
ADDRESS ACCESS TIME



CHIP ENABLE/DISABLE TIMES



WRITE CYCLE



MEMORY TIMING DEFINITIONS

T_{WR} Delay between end of WRITE ENABLE pulse and when DATA OUTPUT becomes valid. (Assuming ADDRESS still valid — not as shown.)

T_{CE} Delay between beginning of CHIP ENABLE low (with ADDRESS valid) and when DATA OUTPUT becomes valid.

T_{CD} Delay between when CHIP ENABLE becomes high and DATA OUTPUT is in off state.

T_{AA} Delay between beginning of valid ADDRESS (with CHIP ENABLE low) and when DATA OUTPUT becomes valid.

T_{WSC} Required delay between beginning of valid CHIP ENABLE and beginning of WRITE ENABLE pulse.

T_{WHD} Required delay between end of WRITE ENABLE pulse and end of valid INPUT DATA.

T_{WP} Width of WRITE ENABLE pulse.

T_{WSA} Required delay between beginning of valid ADDRESS and beginning of WRITE ENABLE pulse.

T_{WSD} Required delay between beginning of valid DATA INPUT and end of WRITE ENABLE pulse.

T_{WD} Delay between beginning of WRITE ENABLE pulse and when DATA OUTPUT is in off state.

T_{WHC} Required delay between end of WRITE ENABLE pulse and end of CHIP ENABLE.

T_{WHA} Required delay between end of WRITE ENABLE pulse and end of valid ADDRESS.